

## P-Channel Enhancement Mode Field Effect Transistor

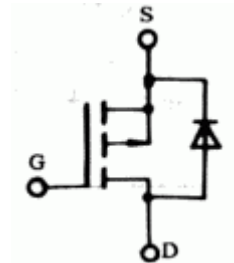
### FEATURES

- Super high dense cell design for low  $R_{DS(ON)}$
- Rugged and reliable
- Simple drive requirement
- SOT-23 package

| PRODUCT SUMMARY |       |                                |
|-----------------|-------|--------------------------------|
| $V_{DSS}$       | $I_D$ | $R_{DS(ON)}$ (m $\Omega$ ) Typ |
| -20V            | -4.0A | 80@ $V_{GS}=-4.5V$             |
|                 |       | 100 @ $V_{GS}=-2.5V$           |



NOTE: The Si2307 is available in a lead-free package



### ABSOLUTE MAXIMUM RATINGS ( $T_A=25^\circ C$ unless otherwise noted)

| Parameter   | Symbol         | Limit      | Unit       |
|---|----------------|------------|------------|
| Drain-Source Voltage                                      | $V_{DS}$       | -20        | V          |
| Gate-Source Voltage                                       | $V_{GS}$       | $\pm 12$   | V          |
| Drain Current-Continuous <sup>a</sup> @ $T_j=125^\circ C$ | $I_D$          | -4.0       | A          |
| - Pulse $d^b$   | $I_{DM}$       | -12        | A          |
| Drain-source Diode Forward Current <sup>a</sup>           | $I_S$          | -1.25      | A          |
| Maximum Power Dissipation <sup>a</sup>                    | $P_D$          | 1.25       | W          |
| Operating Junction and Storage Temperature Range          | $T_j, T_{STG}$ | -55 to 150 | $^\circ C$ |

### THERMAL CHARACTERISTICS

|  |             |     |              |
|--|-------------|-----|--------------|
| Thermal Resistance, Junction-to Ambient <sup>a</sup> | $R_{th JA}$ | 100 | $^\circ C/W$ |
|--|-------------|-----|--------------|

# Si2307

## ELECTRICAL CHARACTERISTICS (T<sub>A</sub>=25°C unless otherwise noted)

| Parameter                        | Symbol              | Condition   | Min  | Typ  | Max  | Unit |
|----------------------------------|---------------------|---|------|------|------|------|
| OFF CHARACTERISTICS              |                     |   |      |      |      |      |
| Drain-Source Breakdown Voltage   | BV <sub>DSS</sub>   | V <sub>GS</sub> =0V, I <sub>D</sub> =-250μA   | -20  |      |      | V    |
| Zero Gate Voltage Drain Current  | I <sub>DSS</sub>    | V <sub>DS</sub> =-16V, V <sub>GS</sub> =0V  |      |      | 1    | μA   |
| Gate-Body Leakage                | I <sub>GSS</sub>    | V <sub>GS</sub> =±10V, V <sub>DS</sub> =0V  |      |      | ±100 | nA   |
| ON CHARACTERISTICS               |                     |   |      |      |      |      |
| Gate Threshold Voltage           | V <sub>GS(th)</sub> | V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =-250μA   | -0.5 | -0.8 | -1.5 | V    |
| Drain-Source On-State Resistance | R <sub>DS(ON)</sub> | V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-4.0A   |      | 80   | 95   | mΩ   |
|                                  |                     | V <sub>GS</sub> =-2.5V, I <sub>D</sub> =-2.0A   |      | 100  | 125  |      |
| Forward Transconductance         | g <sub>FS</sub>     | V <sub>GS</sub> =-5V, I <sub>D</sub> =-5A   |      | 5    |      | S    |
| DYNAMIC CHARACTERISTICS          |                     |   |      |      |      |      |
| Input Capacitance                | C <sub>ISS</sub>    | V <sub>DS</sub> =-10V, V <sub>GS</sub> =0V<br>f=1.0MHz  |      | 586  |      | pF   |
| Output Capacitance               | C <sub>OSS</sub>    |   |      | 101  |      | pF   |
| Reverse Transfer Capacitance     | C <sub>RSS</sub>    |   |      | 59   |      | pF   |
| SWITCHING CHARACTERISTICS        |                     |   |      |      |      |      |
| Turn-On Delay Time               | t <sub>D(ON)</sub>  | V <sub>DD</sub> =-10V<br>I <sub>D</sub> =-4.0A,<br>V <sub>GEN</sub> =-4.5V<br>R <sub>L</sub> =10ohm<br>R <sub>GEN</sub> =6ohm |      | 6.5  |      | ns   |
| Rise Time                        | t <sub>r</sub>      |   |      | 32.1 |      | ns   |
| Turn-Off Delay Time              | t <sub>D(OFF)</sub> |   |      | 58.4 |      | ns   |
| Fall Time                        | t <sub>f</sub>      |   |      | 48   |      | ns   |
| Total Gate Charge                | Q <sub>g</sub>      | V <sub>DS</sub> =-10V, I <sub>D</sub> =-3A<br>V <sub>GS</sub> =-4.5V  |      | 6    |      | nC   |
| Gate-Source Charge               | Q <sub>gs</sub>     |   |      | 1.35 |      | nC   |
| Gate-Drain Charge                | Q <sub>gd</sub>     |   |      | 1.5  |      | nC   |

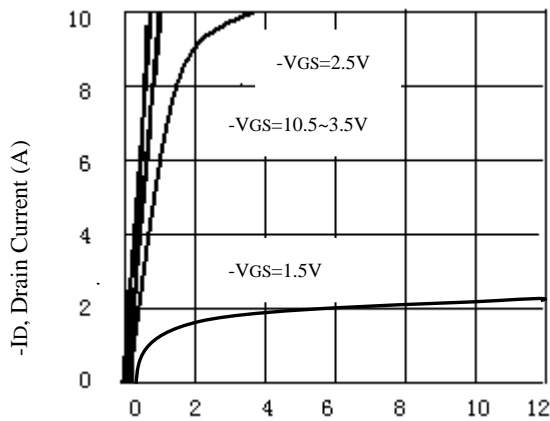
# Si2307

## ELECTRICAL CHARACTERISTICS (TA=25°C unless otherwise noted)

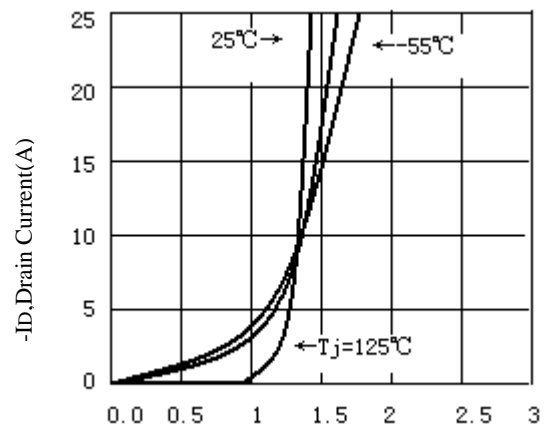
| Parameter                          | Symbol          | Condition                                   | Min | Typ   | Max  | Unit |
|------------------------------------|-----------------|---|-----|-------|------|------|
| DRAIN-SOURCE DIODE CHARACTERISTICS |                 |   |     |       |      |      |
| Diode Forward Voltage              | V <sub>SD</sub> | V <sub>GS</sub> =0V, I <sub>S</sub> =-1.25A |     | -0.81 | -1.2 | V    |

### Notes

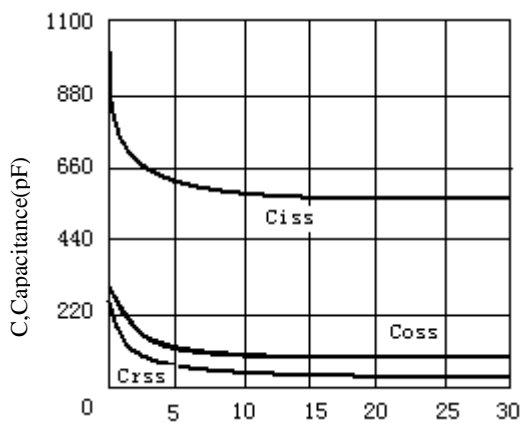
- Surface Mounted on FR4 Board,  $t \leq 10\text{sec}$
- Pulse Test: Pulse Width  $\leq 300\mu\text{s}$ , Duty  $\leq 2\%$
- Guaranteed by design, not subject to production testing.



- V<sub>DS</sub>, Drain-to-Source Voltage (V)  
Figure 1. Output Characteristics



-V<sub>GS</sub>, Gate-to-source Voltage (V)  
Figure 2. Transfer Characteristics



- V<sub>GS</sub>, Drain-to Source Voltage  
Figure 3. Capacitance

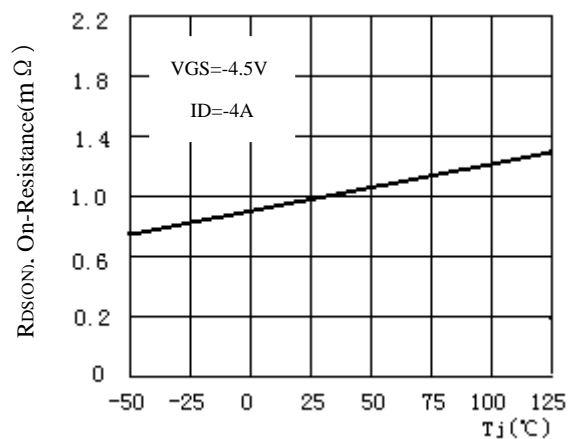
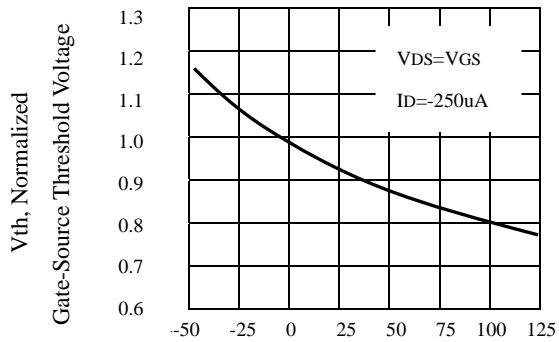
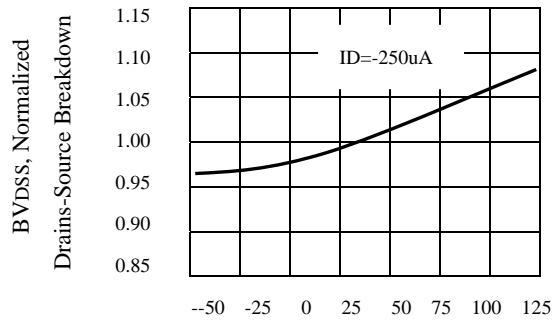


Figure 4. On-Resistance Variation with Temperature

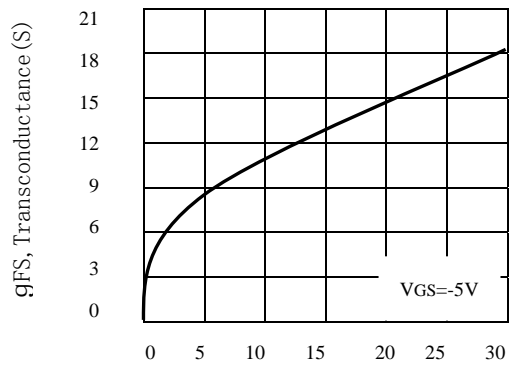
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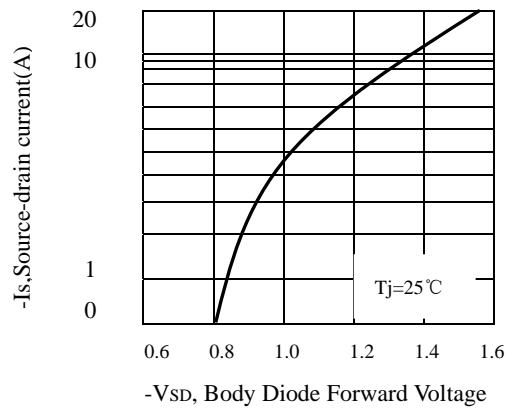
Tj, Junction Temperature(°C)  
Figure5.Gate Threshold Variation With Temperature



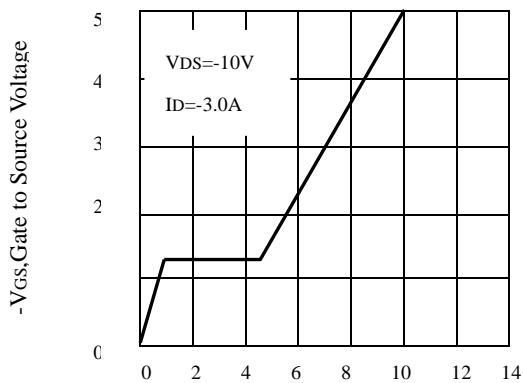
Tj, Junction Temperature (°C)  
Figure6.Breakdown Voltage Variation With Temperature



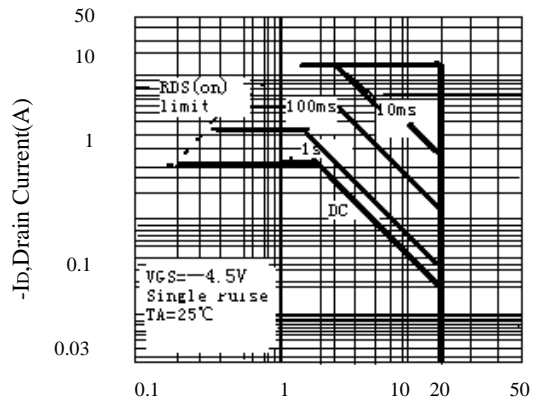
-IDS, Drain-Source Current (A)  
Figure7.Transconductance Variation With Drain Current



-VSD, Body Diode Forward Voltage  
Figure8.Body Diode Forward Voltage Variation with Source Current



Qg, Total Gate Charge (nC)  
Figure9. Gate Charge



-VDS, Drain-Source Voltage(V)  
Figure10.Maximum Safe Operating Area